

10/500427

DT04R&PCT/PTO 2 JUN 2004

HEIWA.014AUS

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shuusuke Kantake ) Group Art Unit  
Serial No. : New U.S. National Stage )  
Application )  
Filed : International Filing Date )  
January 9, 2003 )  
For : TEST EQUIPMENT FOR LSI AS )  
A DEVICE UNDER TEST, )  
JITTER ANALYZER, AND PHASE )  
DIFFERENCE DETECTOR )  
Examiner : Unknown )

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INFORMATION DISCLOSURE STATEMENT

Hon. Commissioner  
of Patents and Trademarks  
Alexandria, VA 22313-1450

Dear Sir:

Enclosed is a form PTO-1449 listing eight prior art references relevant to the above-identified application. A copy of the references is also enclosed herewith.

This information disclosure statement is filed at the time of the instant application concurrently herewith, therefore, no fee is required under 37 CFR 1.97(b)(1).

The prior art references are cited in the International Search Report issued by Japanese Patent Office in the international stage of this case. A copy of the English version of International Search Report is also attached herewith. Since the prior art references are non-English documents, an English abstract is attached to each of the Japanese references.

10/500427  
DT04 Rec'd PCT/PTO 27 JUN 2004

Serial No. : New National Stage Application  
Filed : PCT Filing Date; October 18, 2002

Applicant respectfully requests that the prior art references submitted be considered in the substantive examination of this application.

Respectfully submitted,

MURAMATSU & ASSOCIATES

Dated: 6/28/04

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